

Supporting Information

Vacancy controlled n-p conduction type transition in CuAgSe with superior thermoelectric performance

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Supplementary Figures

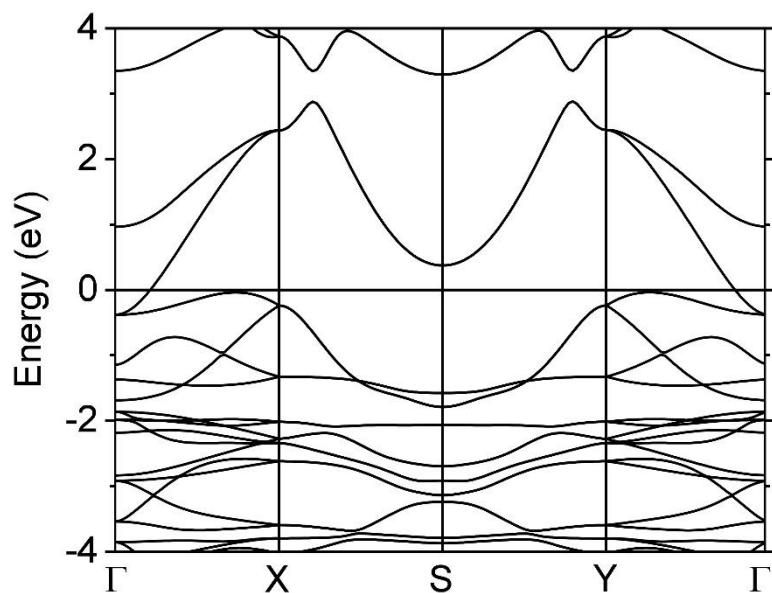


Fig. S1 The calculated band structure of β -CuAgSe.

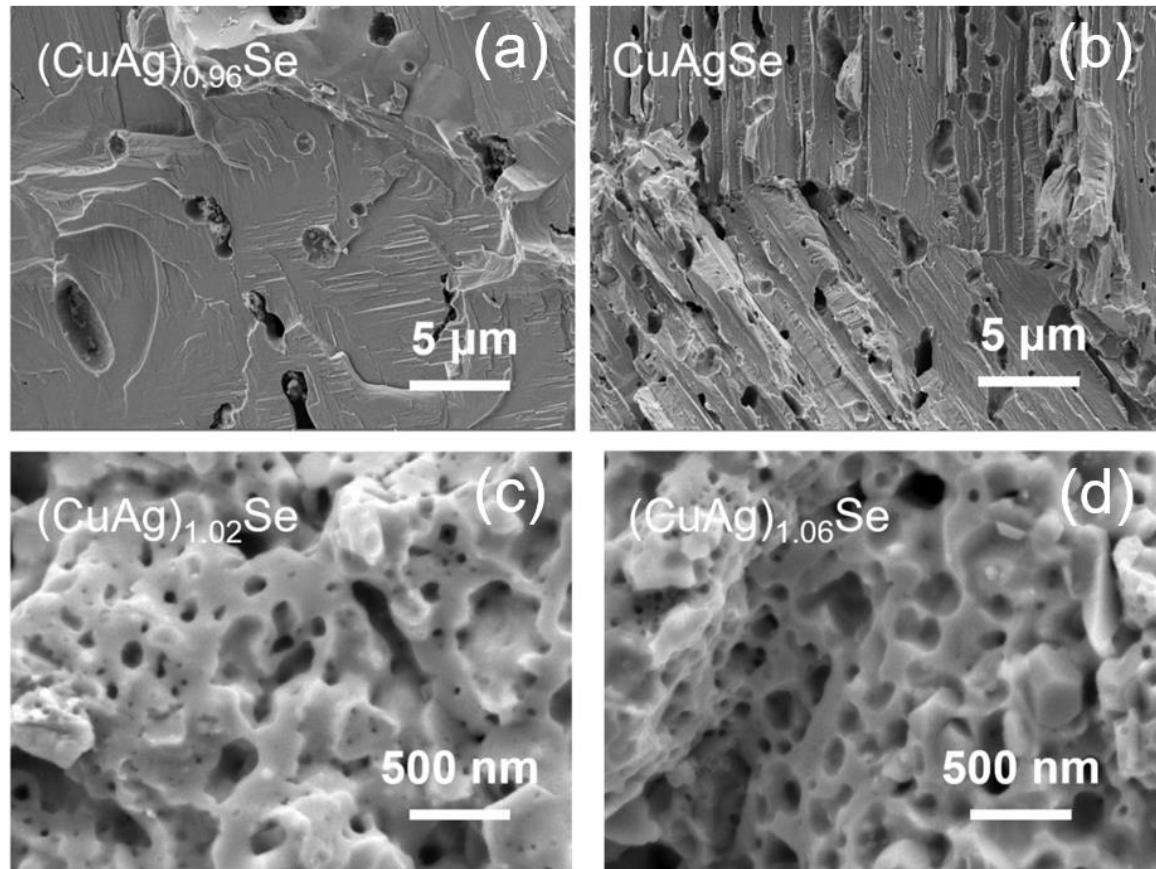


Fig. S2 SEM images of fracture morphology for (a) $(\text{CuAg})_{0.96}\text{Se}$, (b) CuAgSe , (c) $(\text{CuAg})_{1.02}\text{Se}$, (d) $(\text{CuAg})_{1.06}\text{Se}$.

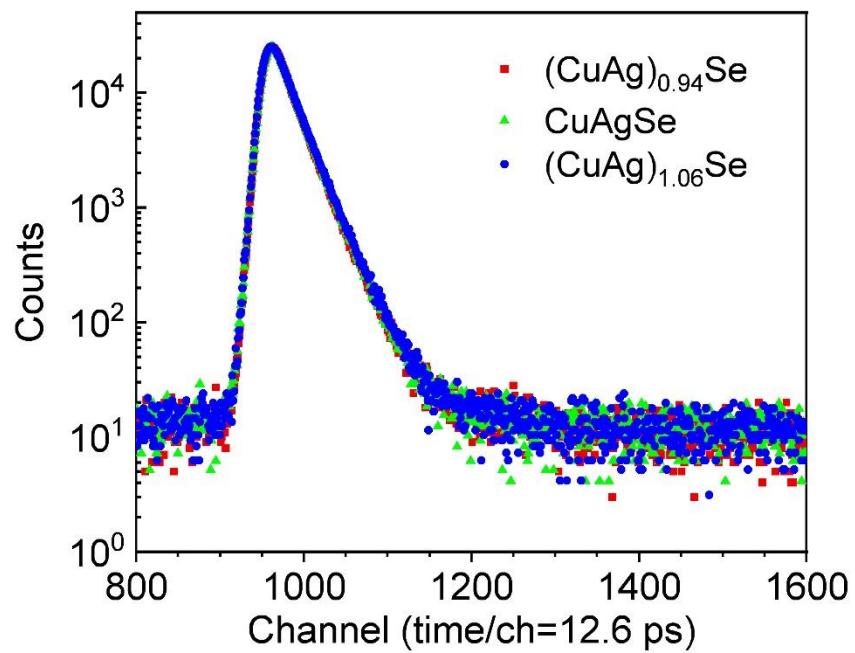


Fig. S3 Positron lifetime spectra of $(\text{CuAg})_{0.94}\text{Se}$, CuAgSe and $(\text{CuAg})_{1.06}\text{Se}$.

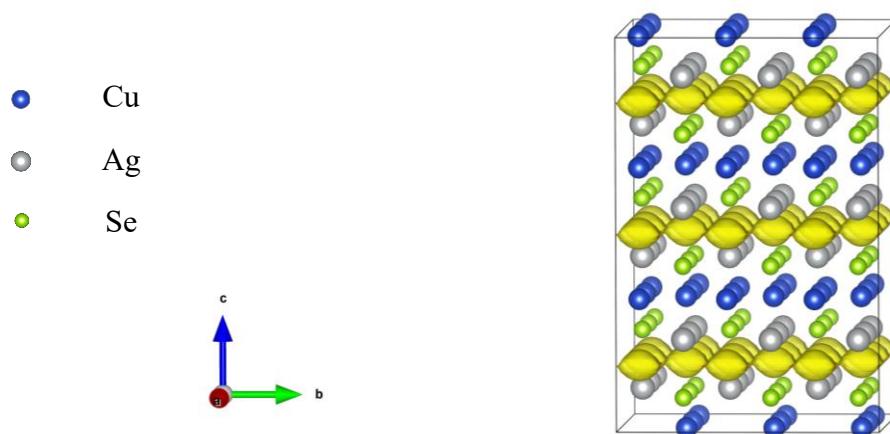


Fig. S4 Positron density distribution in the bulk state of CuAgSe .

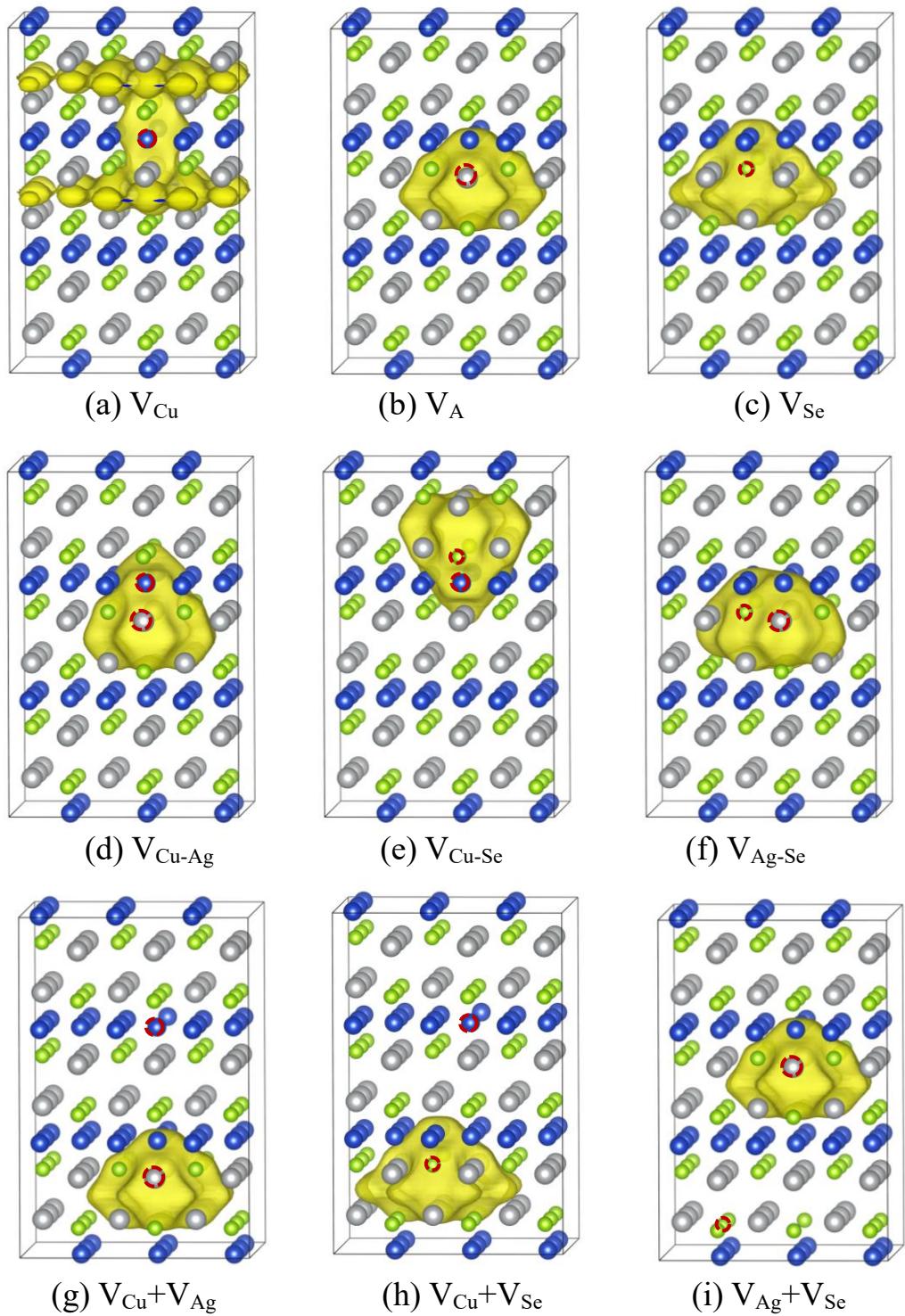


Fig. S5 Positron density distribution in the trapping state with various defects in CuAgSe.

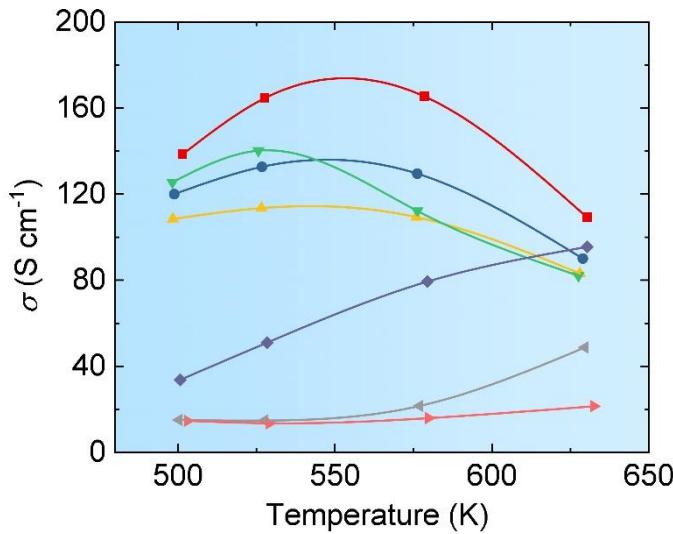


Fig. S6 Temperature-dependent conductivity of $(\text{CuAg})_x\text{Se}$ ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$) after phase transition.

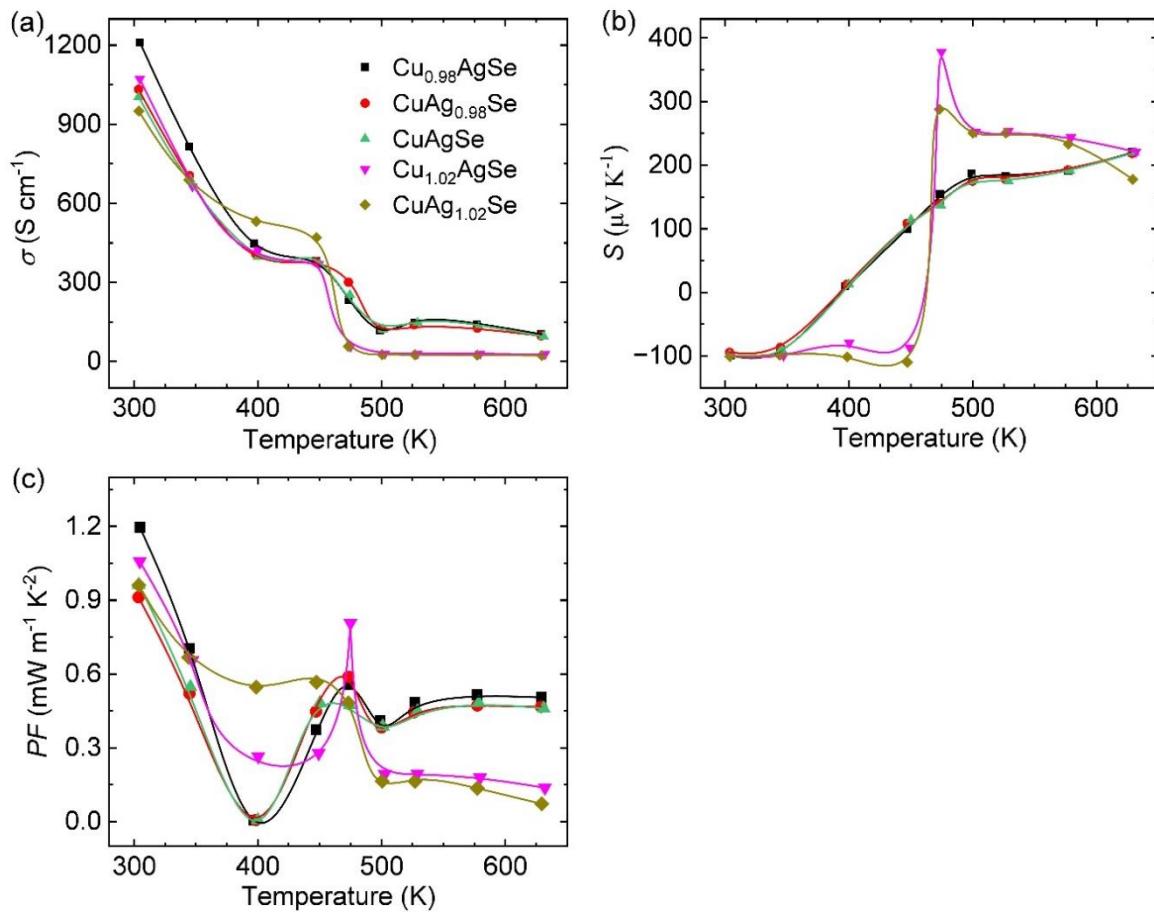


Fig. S7 The temperature-dependent electric transport properties of $\text{Cu}_{1.02}\text{AgSe}$, $\text{CuAg}_{1.02}\text{Se}$, CuAgSe , $\text{Cu}_{0.98}\text{AgSe}$, $\text{CuAg}_{0.98}\text{Se}$: (a) conductivity, (b) seebeck coefficient, (c) power factor.

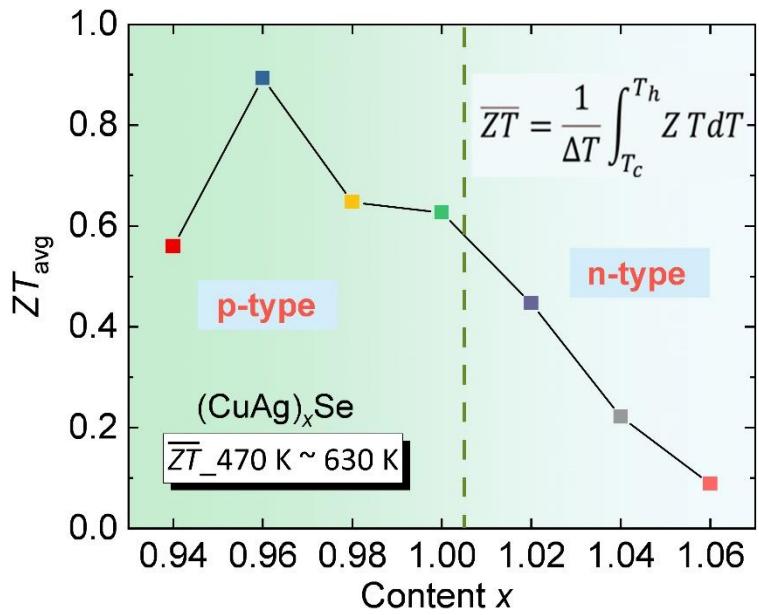


Fig. S8 The average ZT of $(\text{CuAg})_x\text{Se}$ ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$) of $470 \sim 630$ K.

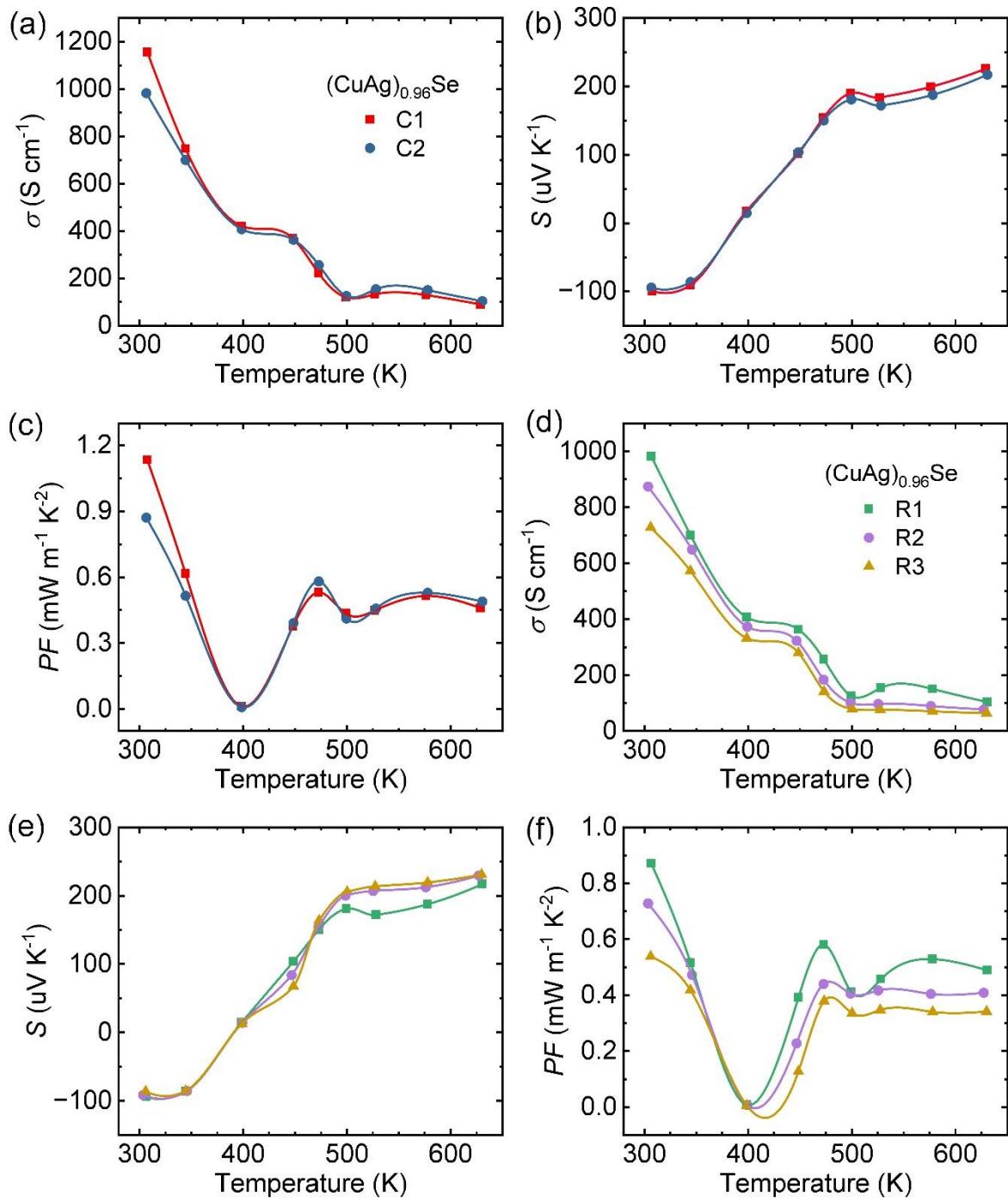


Fig. S9 The chemical composition reproducibility of temperature-dependent electric transport properties of $(\text{CuAg})_{0.96}\text{Se}$ (C1 and C2 are sample-1 and sample-2 of different batches): (a) conductivity, (b) seebeck coefficient, (c) power factor; repeated cycle tests (R1, R2, R3) of sample-2: (d) conductivity, (e) seebeck coefficient, (f) power factor.

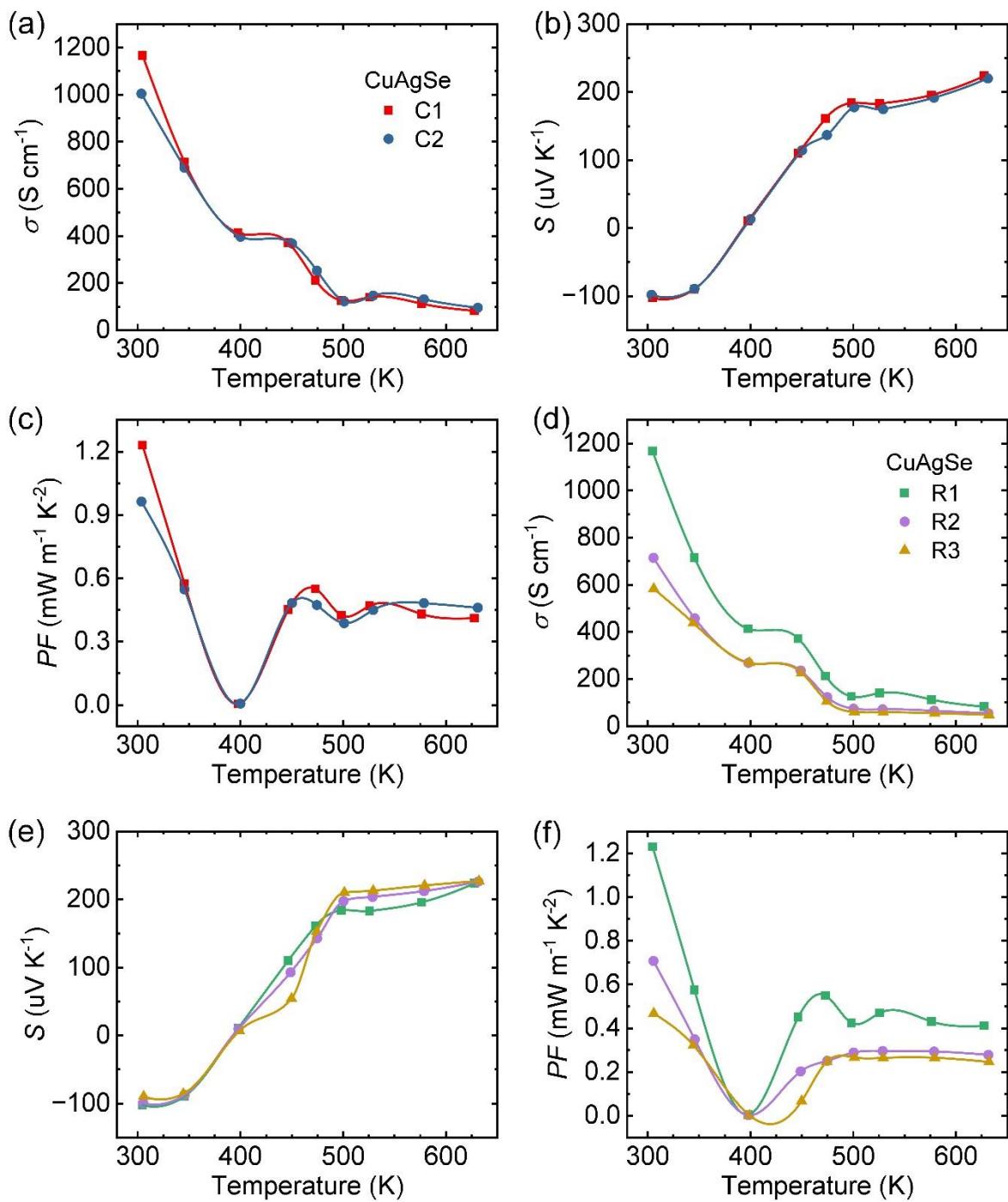


Fig. S10 The chemical composition reproducibility of temperature-dependent electric transport properties of CuAgSe (C1 and C2 are sample-1 and sample-2 of different batches): (a) conductivity, (b) seebeck coefficient, (c) power factor; repeated cycle tests (R1, R2, R3) of sample-1: (d) conductivity, (e) seebeck coefficient, (f) power factor.

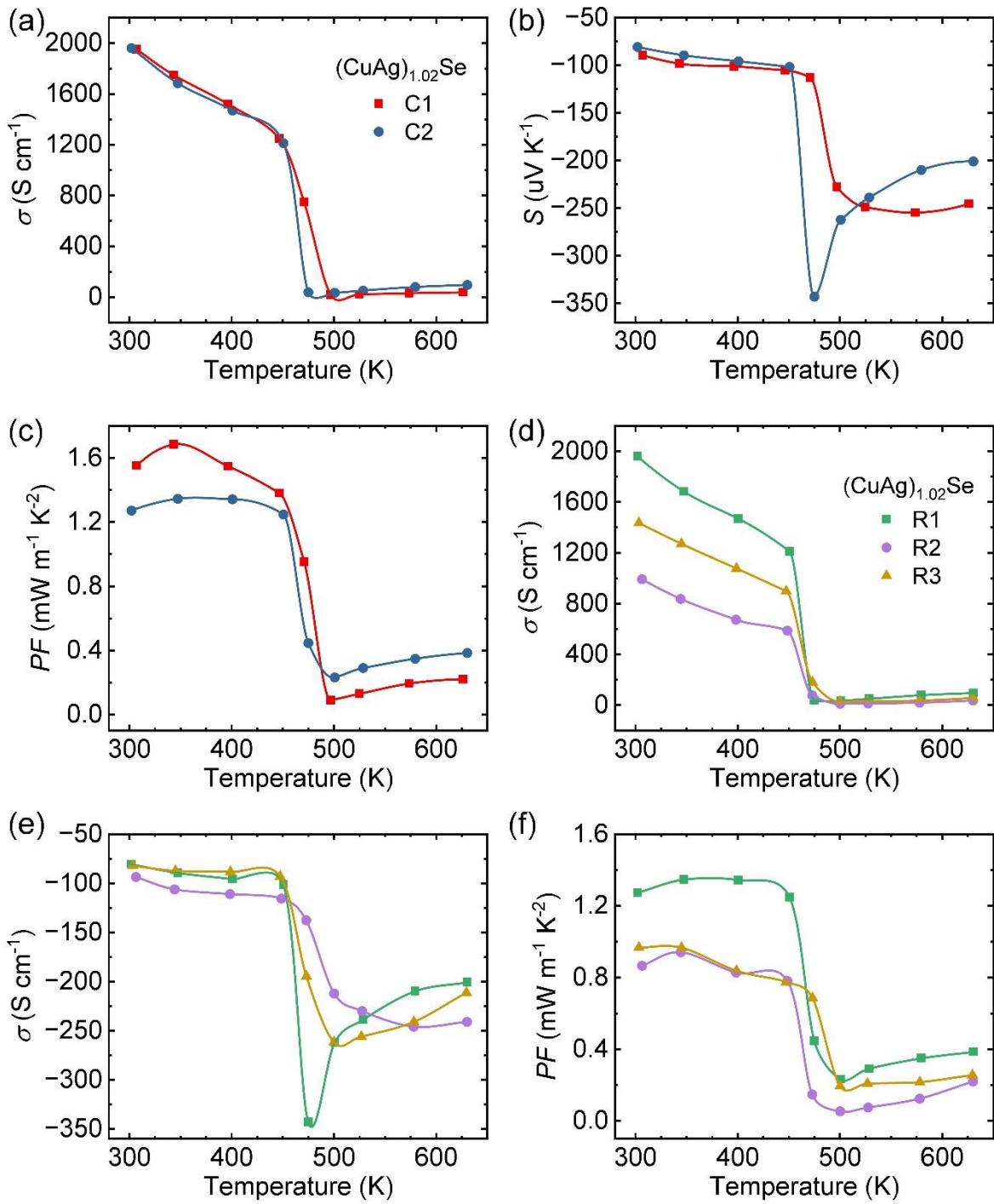


Fig. S11 The chemical composition reproducibility of temperature-dependent electric transport properties of $(\text{CuAg})_{1.02}\text{Se}$ (C1 and C2 are sample-1 and sample-2 of different batches): (a) conductivity, (b) seebeck coefficient, (c) power factor; repeated cycle tests (R1, R2, R3) of sample-2: (d) conductivity, (e) seebeck coefficient, (f) power factor.

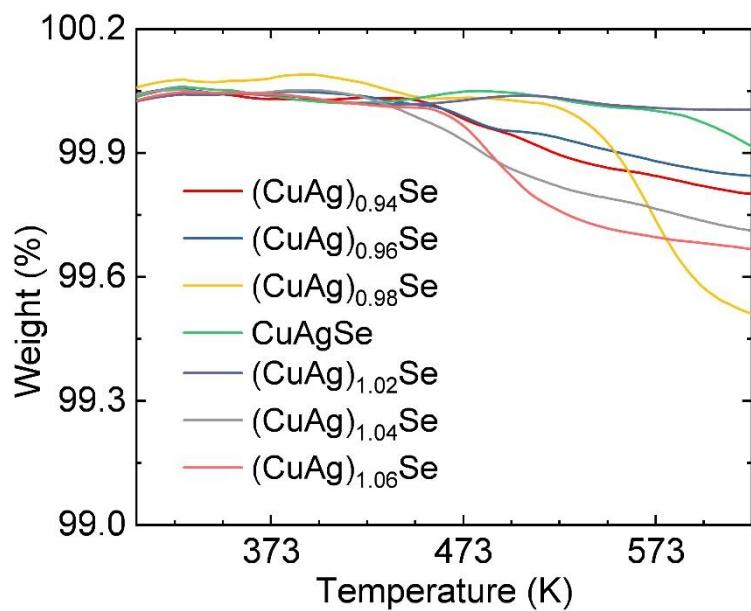


Fig. S12 Thermogravimetric curve of $(\text{CuAg})_x\text{Se}$ from 300 K to 623 K ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$).

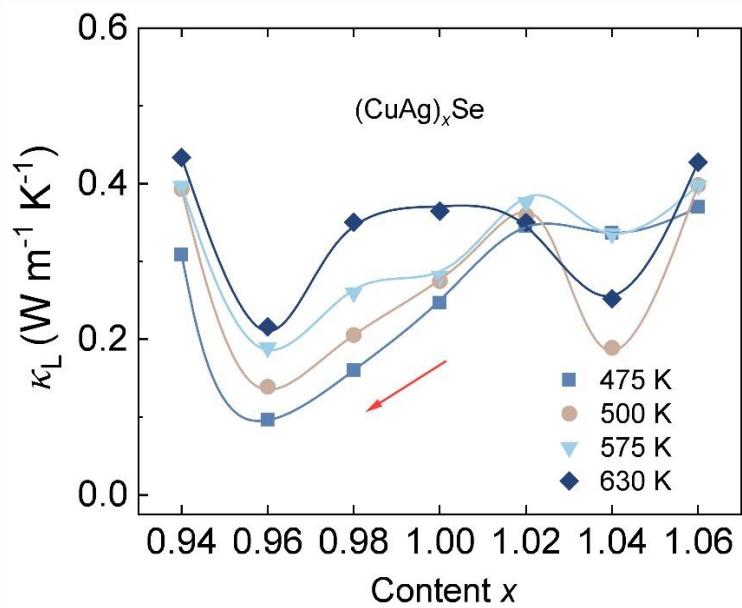


Fig. S13 The CuAg content x dependent lattice thermal conductivity at several different temperatures.

Supplementary Tables

Table S1. Positron lifetime τ_1 and τ_2 , intensity of each lifetime component I_1 and I_2 , average positron lifetime of $(\text{CuAg})_x\text{Se}$ ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$).

samples	τ_1 (ps)	τ_2 (ps)	I_1 (%)	I_2 (%)	Average lifetime (ps)
$(\text{CuAg})_{0.94}\text{Se}$	143	272	13	87	255
$(\text{CuAg})_{0.96}\text{Se}$	171	271	12	88	260
$(\text{CuAg})_{0.98}\text{Se}$	176	272	17	83	262
CuAgSe	179	281	16	84	264
$(\text{CuAg})_{1.02}\text{Se}$	148	289	15	85	267
$(\text{CuAg})_{1.04}\text{Se}$	176	291	22	78	266
$(\text{CuAg})_{1.06}\text{Se}$	159	290	16	84	269

Table S2. The Hall carrier concentration, Hall mobility, effective mass and relaxation time of $(\text{CuAg})_x\text{Se}$ ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$) at room temperature.

samples	n_H (cm^{-3})	μ_H ($\text{cm}^2 \text{ V}^{-1} \text{ s}^{-1}$)	m^*/m_e	τ_R (10^{-13} s)
$(\text{CuAg})_{0.94}\text{Se}$	-4.47×10^{18}	1714	0.135	1.315
$(\text{CuAg})_{0.96}\text{Se}$	-4.02×10^{18}	1795	0.131	1.343
$(\text{CuAg})_{0.98}\text{Se}$	-4.25×10^{18}	1763	0.142	1.431
CuAgSe	-3.35×10^{18}	2176	0.121	1.504
$(\text{CuAg})_{1.02}\text{Se}$	-5.35×10^{18}	2286	0.125	1.627
$(\text{CuAg})_{1.04}\text{Se}$	-3.88×10^{18}	2094	0.133	1.591
$(\text{CuAg})_{1.06}\text{Se}$	-4.00×10^{18}	2582	0.111	1.636

Table S3. The temperature dependent Hall carrier concentration, hall mobility, effective mass of
 (a) $(\text{CuAg})_{0.96}\text{Se}$, (b) CuAgSe and (c) $(\text{CuAg})_{1.02}\text{Se}$.

(a)

$(\text{CuAg})_{0.96}\text{Se}$	n_H (cm^{-3})	μ_H ($\text{cm}^2 \text{ V}^{-1} \text{ s}^{-1}$)	m^*/m_e
323K	-4.46×10^{18}	1380	0.126
373K	-4.27×10^{18}	841	0.035
423K	-7.69×10^{18}	321	0.082
473K	-1.78×10^{19}	78	0.415
573K	-4.90×10^{20}	1.66	4.677
623K	-3.69×10^{20}	1.60	4.418

(b)

CuAgSe	n_H (cm^{-3})	μ_H ($\text{cm}^2 \text{ V}^{-1} \text{ s}^{-1}$)	m^*/m_e
323K	-3.84×10^{18}	1569	0.116
373K	-3.71×10^{18}	936	0.035
423K	-6.47×10^{18}	378	0.077
473K	-1.46×10^{19}	91	0.385
573K	-4.78×10^{20}	1.49	4.458
623K	-3.28×10^{20}	1.61	4.024

(c)

$(\text{CuAg})_{1.02}\text{Se}$	n_H (cm^{-3})	μ_H ($\text{cm}^2 \text{ V}^{-1} \text{ s}^{-1}$)	m^*/m_e
323K	-4.31×10^{18}	2658	0.107
373K	-3.97×10^{18}	2491	0.097
423K	-5.28×10^{18}	1604	0.112
473K	-4.80×10^{18}	170	0.741
573K	-1.05×10^{18}	449	0.089
623K	-1.38×10^{18}	421	0.089

Table S4. The density values of $(\text{CuAg})_x\text{Se}$ ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$).

Sample	Density (g/cm ³)
$(\text{CuAg})_{0.94}\text{Se}$	6.89
$(\text{CuAg})_{0.96}\text{Se}$	6.78
$(\text{CuAg})_{0.98}\text{Se}$	6.84
CuAgSe	7.19
$(\text{CuAg})_{1.02}\text{Se}$	7.17
$(\text{CuAg})_{1.04}\text{Se}$	6.94
$(\text{CuAg})_{1.06}\text{Se}$	7.15

Table S5. The Lorentz number (a) calculated according to equation (13), (b) obtained by equation: $L = 1.5 + \exp[-\frac{|S|}{116}]$.

(a)

L (V ² K ⁻²)	$(\text{CuAg})_{0.96}\text{Se}$	$(\text{CuAg})_{0.98}\text{Se}$	CuAgSe	$(\text{CuAg})_{1.02}\text{Se}$	$(\text{CuAg})_{1.04}\text{Se}$
303 K	1.92×10^{-8}	1.90×10^{-8}	1.90×10^{-8}	2.02×10^{-8}	1.90×10^{-8}
348 K	1.96×10^{-8}	1.97×10^{-8}	1.97×10^{-8}	1.97×10^{-8}	1.86×10^{-8}
400 K	2.41×10^{-8}	2.41×10^{-8}	2.43×10^{-8}	1.93×10^{-8}	1.84×10^{-8}
450 K	1.91×10^{-8}	1.92×10^{-8}	1.87×10^{-8}	1.91×10^{-8}	1.81×10^{-8}
475 K	1.71×10^{-8}	1.68×10^{-8}	1.70×10^{-8}	1.51×10^{-8}	1.62×10^{-8}
500 K	1.64×10^{-8}	1.64×10^{-8}	1.65×10^{-8}	1.55×10^{-8}	1.88×10^{-8}
523 K	1.65×10^{-8}	1.63×10^{-8}	1.65×10^{-8}	1.57×10^{-8}	2.44×10^{-8}
573 K	1.62×10^{-8}	1.62×10^{-8}	1.63×10^{-8}	1.61×10^{-8}	1.54×10^{-8}
630 K	1.58×10^{-8}	1.58×10^{-8}	1.59×10^{-8}	1.62×10^{-8}	1.58×10^{-8}

(b)

L (V ² K ⁻²)	(CuAg) _{0.96} Se	(CuAg) _{0.98} Se	CuAgSe	(CuAg) _{1.02} Se	(CuAg) _{1.04} Se
303 K	1.93×10 ⁻⁸	1.91×10 ⁻⁸	1.91×10 ⁻⁸	2.00×10 ⁻⁸	1.91×10 ⁻⁸
348 K	1.96×10 ⁻⁸	1.97×10 ⁻⁸	1.96×10 ⁻⁸	1.96×10 ⁻⁸	1.88×10 ⁻⁸
400 K	2.36×10 ⁻⁸	2.35×10 ⁻⁸	2.41×10 ⁻⁸	1.94×10 ⁻⁸	1.86×10 ⁻⁸
450 K	1.92×10 ⁻⁸	1.92×10 ⁻⁸	1.89×10 ⁻⁸	1.92×10 ⁻⁸	1.84×10 ⁻⁸
475 K	1.76×10 ⁻⁸	1.74×10 ⁻⁸	1.75×10 ⁻⁸	1.55×10 ⁻⁸	1.68×10 ⁻⁸
500 K	1.69×10 ⁻⁸	1.70×10 ⁻⁸	1.71×10 ⁻⁸	1.60×10 ⁻⁸	1.90×10 ⁻⁸
523 K	1.70×10 ⁻⁸	1.69×10 ⁻⁸	1.71×10 ⁻⁸	1.63×10 ⁻⁸	2.45×10 ⁻⁸
573 K	1.68×10 ⁻⁸	1.68×10 ⁻⁸	1.69×10 ⁻⁸	1.66×10 ⁻⁸	1.59×10 ⁻⁸
630 K	1.64×10 ⁻⁸	1.64×10 ⁻⁸	1.65×10 ⁻⁸	1.68×10 ⁻⁸	1.64×10 ⁻⁸

Table S6. The grain size of (CuAg)_xSe ($x = 0.94, 0.96, 0.98, 1, 1.02, 1.04, 1.06$) obtained from XRD diffraction peaks.

Sample	Grain size (nm)
(CuAg) _{0.94} Se	30
(CuAg) _{0.96} Se	26
(CuAg) _{0.98} Se	36
CuAgSe	33
(CuAg) _{1.02} Se	35
(CuAg) _{1.04} Se	25
(CuAg) _{1.06} Se	29